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Industry Canada
Certification & Engineering Bureau
P.O. Box 11490, Station H
3701 Carling Ave., Building 94
Ottawa, Ontario K2H 8S2

Subject: Attestation of Test Reports IC Certification No: 649E-XE500T1C

To Whom It May Concern:

This is to attest that the test reports:

- RFI-RPT-RP89958JD03A V5;
- RFI-RPT-RP89958JD03B V4;
- RFI-RPT-RP89958JD04A V6,
- RFI-RPT-RP89958JD05A V4;
- RFI-RPT-RP89958JD05B V6;
- RFI-RPT-RF89958JD05C V4;

for IC # : 649E-XE500T1C cover both versions of SKU#2 and SKU#3 based on preliminary review indicating that the version without NFC represented the worst case for the DS and NII.

Clarification of terms:

- SKU#2: Version without NFC; IC #: 649E-XE500T1C;
- SKU#3: Version with NFC; IC #: 649E-XE500T1CN;

Best Regards

John SC Lee
Manager
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